



# Ion sensitivity from current hysteresis in InAs nanowire field-effect transistors functionalized with ionophore-doped fluorosilicone membranes

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## ARTICLE INFO

### Keywords:

InAs  
Nanowire  
Field-effect transistor  
Hysteresis  
Ionophore  
Ion sensor

## ABSTRACT

Trapping of environmental charges in surface states typically dominates electrical transport in nanostructured field-effect transistors (FETs) applied as sensors. Such surface effects produce exceptional sensitivity, yet time dependencies on experimental timescales simultaneously results in hysteresis of FET conductance and signal instability. Whereas hysteresis is usually suppressed by means of chemical surface treatments, here we study it as a source of information for ion sensing. Ion-sensitive FETs were prepared by coupling InAs nanowires to fluorosilicone membranes doped with Na<sup>+</sup> ionophores. From cyclic transfer characteristics in electrolytes of varying concentration, potentiometric and hysteretic calibration curves were obtained. The observed hysteresis was attributed to changes in membrane capacitance by redox reactions between ionized donor-like traps at the InAs surface and electroactive membrane constituents. Hysteresis was correlated to the ion potential through a model and demonstrated a filtering effect that stabilized the hysteretic response against potential drifts. Furthermore, the model elucidated the ability to modulate ion sensitivity by controlling the initial density of ionized traps via electrostatic polarization by the gate. In this mode of active operation, we demonstrate enhancement above the Nernstian limit with linear calibrations of  $(-77.5 \pm 3.2$  to  $-80.7 \pm 3.0$  mV/dec) despite the presence of non-equilibrium ion fluxes.

## 1. Introduction

Development of the next-generation of chemical and biological sensors with electrical read-outs increasingly targets field-effect transistors (FETs) employing nanostructured materials such as nanowires (NWs) and nanotubes [1,2]. By exposing the FET gate to the environment, the electric charge of adsorbed species is transduced and amplified as a current between source and drain electrodes (see Fig. 1a). Facile measurement is possible even as biosensors are miniaturized, contributing to its appeal in applications such as point-of-care diagnostics [3,4].

The prototypical biosensor is the ion-sensitive FET (ISFET) [5], and recent advancements have focussed on Si NWs [1,6]. This approach pairs well-studied Si chemistries (e.g. silanization [7,8]) with the benefits of nanostructure, such as enhanced sensitivity in FET sub-threshold regime [9] or geometric reduction of Debye screening [10]. However, a

key challenge in developing NW biosensors is controlling the dominating influence of surface trap states on electrical transport [11]. This is often addressed by a passivating oxide [12]; for instance, the ideal NW biosensor modelled in Ref. [10] assumes no surface effects and expresses sensitivity in terms of the geometry (i.e. curvature) of the FET gate and electrical double layer capacitance.

Unfortunately, this view spurns information available from the interaction between surface states and analyte, which can manifest as random telegraph (1/f) noise when environmental charges are repeatedly exchanged with trap states [13,14]. Studies using this approach demonstrated enhanced limits of detection or sensitivity, albeit requiring sophisticated measurement schema not conducive towards *in situ* applications. Indeed, investigation of similar noise in our InAs NWFETs led to the realization of its exceptional charge sensitivity [15] and potential for biosensing.

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The InAs surface intrinsically accumulates electrons, due to large surface state densities in a non-stoichiometric native oxide [16–18]. These states interact with adsorbed molecules, modulating electrical transport in InAs NWFETs, and have demonstrated applicability for sensing [19–21]. Furthermore, sensing of individual molecular dipoles at ultra-low concentrations has recently been demonstrated [22]. However, the trade-off for high sensitivity is again the dominating effect of surface states, which, in InAs, exhibit capture and emission rates on experimental timescales [23,24]. This produces hysteresis in measurements of FET current and is typically considered a problem to be eliminated. For instance, previous work on ISFETs using InAs NWs passivated the native oxide with Al<sub>2</sub>O<sub>3</sub> and produced biosensors capable of detecting pH and protein charges [25].

In this study, rather than disparage hysteresis, we instead leverage it to obtain sensing responses to sodium cations (Na<sup>+</sup>) that are more stable than the interface potential approximated by the FET threshold voltage ( $V_T$ ). A model is developed to quantify NWFET current hysteresis and elucidate the origin of its ion sensitivity. The model reveals a key design parameter—the initial density of ionized trap states—which can enhance or suppress the sensitivity of the hysteretic response coupled to it. Experiments in simple electrostatic manipulation (i.e. polarization) of this parameter are presented as proof-of-concept for active operation of NW-ISFETs to modulate ion sensitivities.

## 2. Material and methods

InAs NWFETs were sensitized to Na<sup>+</sup> by coupling to fluorosilicone (FPS) polymer membranes uniformly doped with ionophores, similar to those used in ion-selective electrodes, shown schematically in Fig. 1. This semi-permeable membrane develops a potential localized at the polymer/electrolyte interface ( $\psi_{\text{int}}$ ) dependent on Na<sup>+</sup> activity ( $a_{\text{Na}^+}$ ) in the bulk solution that is described by the Nernst equation [26,27]:

$$\psi_{\text{int}} = 2.303 \frac{RT}{F} \log \frac{a_{\text{Na}^+, \text{bulk}}}{a_{\text{Na}^+, \text{mem}}} + \psi_o \quad (1)$$

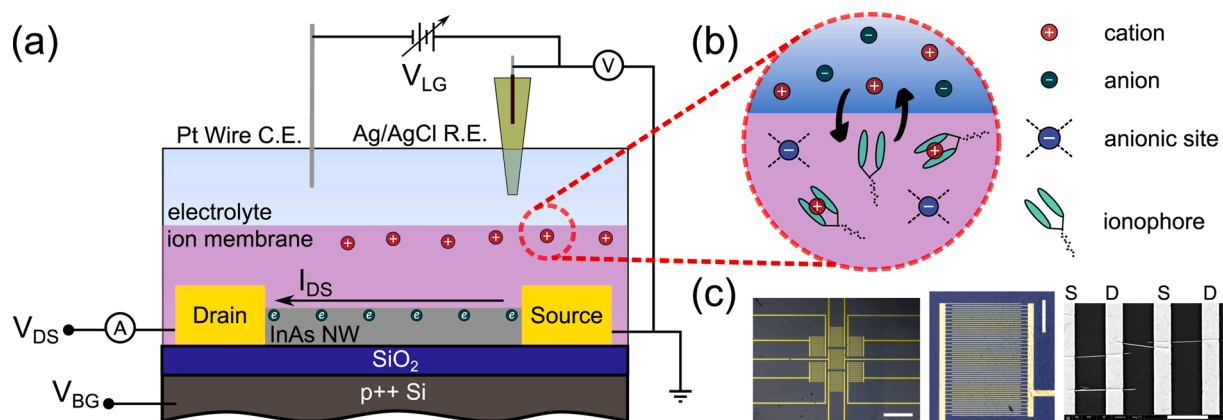
where  $RT/F$  has its typical thermodynamic meaning, giving an ideal slope of 59.2 mV/decade of  $a_{\text{Na}^+, \text{bulk}}$  at ambient.  $\psi_o$  encompasses the standard chemical potential, free energy change of complexation, and other system constants (e.g. junction potential). Therefore,  $\psi_{\text{int}}$  acts in series with a gating potential ( $V_{LG}$ ) set by a reference/counter electrode

established protocols on thin-film InGaZnO ISFETs [29], and stability of Na<sup>+</sup> sensitivity upwards of 1 month was demonstrated on paper-based electrodes [30]. Further details are reported in the Supplementary Information (SI) §S1 and elsewhere for InAs NWFET [22] and ion-membrane [29] fabrication.

DC electrical characterization and sensing experiments were performed with either Keysight B1500A or Keithley 4200 analyzers, with source-measure units as dedicated channels for the drain electrode, RE/CE pair in a modified Kelvin probe configuration<sup>2</sup> [31], and back-gate electrode. The source electrode was connected to instrument ground. NWFETs operated in the linear regime by biasing the drain to  $V_{DS} = 10$  mV and transfer curves ( $I_{DS}$  vs.  $V_{LG}$ ) were measured by sweeping  $V_{LG}$  at a rate of ca. 30 mV/s via a Pt CE referenced to a Ag/AgCl in 3M KCl(aq) RE. The RE was connected to test solution through an agar gel salt bridge with its junction positioned within ca. 2 mm of the membrane/electrolyte interface. The back-gate was held constant at  $V_{BG} = 0$  V. Photographs of the measurement apparatus can be seen in Fig. S1.

Devices employed in this study were firstly qualified by collecting transfer characteristics at major fabrication steps as described in SI §S1.4. In brief, suitable devices demonstrated minimal leakage currents and sufficient switching operation (viz. leakage current as 0.1% of  $I_{DS}$ , transconductance >10  $\mu$ S and subthreshold swing <500 mV/dec) under electrolyte-gating. For analysis,  $V_T$  was extracted by extrapolating a least-squares fit of the linear region of a transfer curve to the abscissa.

Test solutions with [Na<sup>+</sup>] ranging from 5 mM to 1000 mM were buffered with 20 mM HEPES at physiological pH ~7.3 to control for the impact of H<sup>+</sup> activity and preparation is described in SI §S1.3. In sensing experiments, 10  $\mu$ L aliquots of solution were dispensed by micro-pipette and measurements proceeded in order of increasing then decreasing [Na<sup>+</sup>]. Test solutions were exchanged four times for every step of [Na<sup>+</sup>], with the fourth aliquot used to collect a transfer curve. Additionally, the tips of RE and CE were wetted during exchanges to mitigate any residues. Solutions remained in contact with the membrane for 2 min with  $V_{LG} = 0$  V prior to a measurement, taken 3 times per step, of which the final is reported. To electrostatically manipulate ionized trap state density, NW-ISFETs were polarized by biasing  $V_{LG}$  at the starting potential of a sweep during the solution contact time.



**Fig. 1.** (a) Schematic diagram of an InAs NWFET coupled with ion-selective FPS membrane and electrical connections. (b) Magnification of ion-selective FPS membrane. Complexation is represented by arrows to/from a cation and ionophore species. (c) Left to right: optical, optical, and SEM micrographs of an InAs multi-NWFET array with alternating source (S) and drain (D) contacts. Scale bars are 500  $\mu$ m, 100  $\mu$ m and 5  $\mu$ m, respectively.

(RE/CE). To better focus on NWFET hysteresis, Na<sup>+</sup> was chosen as a model analyte in conjunction with a well-established crown ether-based ionophore (bis(12-crown-4)) demonstrating Nernstian sensitivity [28]. The selectivity of this membrane system was previously evaluated with

<sup>2</sup> The RE serves as the potential sensing contact, while the CE is used to force current.

### 3. Results and discussion

#### 3.1. Quantified hysteresis model

Data from a representative  $\text{Na}^+$  sensing experiment without polarization are shown in Fig. 2. The transfer curves in Fig. 2a, b are characteristic of the n-type NW-ISFETs fabricated from our InAs NWs under electrolyte-gating and  $I_{DS}$  hysteresis is observed in their lineshape. For comparison, Fig. S3 shows data before and after membrane deposition. Generally, upward (i.e.  $dV_{LG}/dt > 0$ ) sweeps showed smaller  $I_{DS}$  regardless of whether the sweep led or trailed. Thus, hysteresis in these electrolyte-gated, membrane-coupled InAs NW-ISFETs possesses an anti-clockwise character, contrasting with previous observations of back-gated devices with native oxide surfaces in vacuum and air (i.e. clockwise) [23,24].

Investigations of electrolyte-gated, ambipolar graphene FETs [32] attributed such anti-clockwise  $I_{DS}$  hysteresis to the charging of the electrical double layer capacitor ( $C_{DL}$ ) by the gate electrode. For instance, at the turning point of the transfer measurement after applying positive electric field, the region near the FET gate interface is enriched in cations, resulting in increased  $I_{DS}$  (i.e. due to compensated carrier density in n-type devices). In our NWFETs, the leakage current (i.e.  $I_{LG}$ ) data in Fig. S3 demonstrates this capacitive charging by its lineshape (i.e. with minimal electrochemical interference) and a magnitude of integral capacitance (estimated by the injected charge and geometric area in solution contact,  $C = \int I_{LG} dt \cdot A^{-1} (\max V_{LG} - \min V_{LG})^{-1}$ ) on the order of  $10^{-5}$  F/cm<sup>2</sup> (cf.  $2$  to  $8 \times 10^{-5}$  F/cm<sup>2</sup> for typical electrical double layers [33]). Note that for analyte charges localized in the membrane layer  $C_{DL}$  is considered to be in parallel [10] with the gate capacitance stack ( $C_g$  as defined in §2.1), and thus the magnitude of  $C_{DL}$  dominates coupling of applied potentials to carrier density in the NW (alternatively, the effect of adsorbed charges at the NW/electrolyte interface on the potential in the channel).

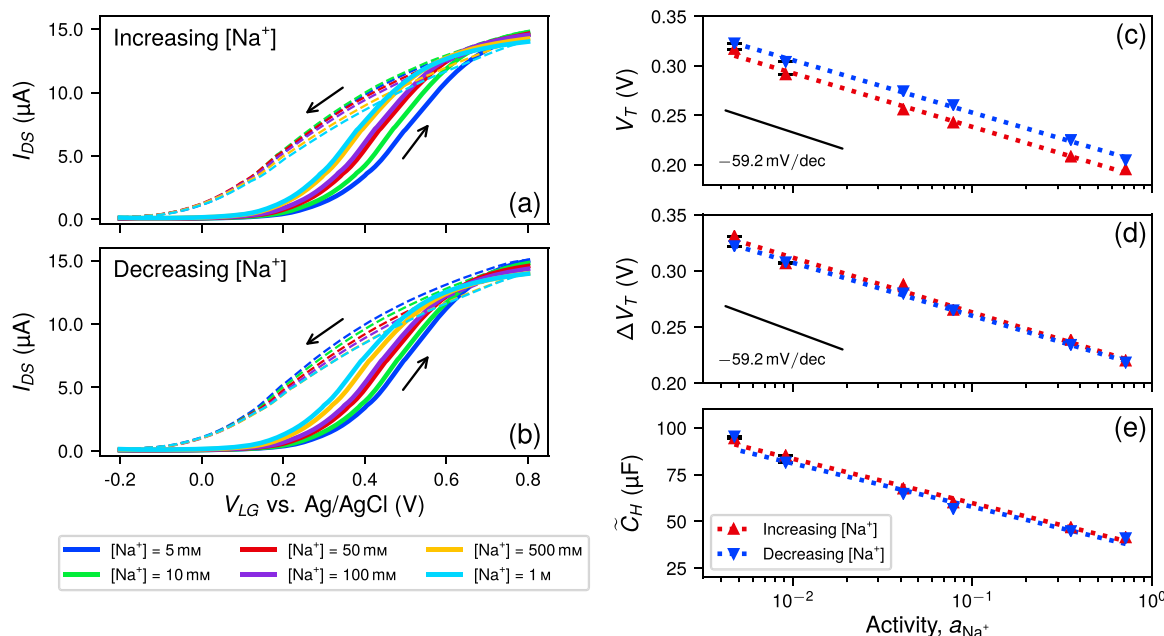
Hence, idealized models of NWFET ion sensitivity often forego consideration of changes to  $C_g$ , which for our devices is essentially the series capacitance of the InAs native oxide and ion-membrane stack. Note that we neglect the NW quantum capacitance as NWFETs are operated in the linear regime and InAs is intrinsically accumulating. However, in comparing transfer curves and leakage current data before

and after membrane deposition it is obvious that capacitive charging cannot fully account for the  $I_{DS}$  hysteresis observed in Fig. 2a, b. That is,  $I_{DS}$  lineshape is significantly altered despite qualitatively and quantitatively similar leakage current behaviour. This indicates that the InAs surface state distribution is altered, but not passivated, by the deposition of FPS ion-membranes. Therefore, understanding how the NW potential (and FET conductance) is affected by analyte charges (i.e. NW-ISFET sensitivity) requires tracking the population of surface states at the interior NW/membrane interface in tandem with  $C_g$ .

Qualitatively, we consider the interaction between donor-like InAs surface states and tetraorganoborate anionic sites in the membrane. Incorporated from sodium salts, these borates possess a negative charge and set the NWFET in enhancement-mode (i.e. positive  $V_T$ ). Subsequent lowering of energy band levels in the channel by raising  $V_{LG}$  provides an overpotential and drives oxidation of borates into stable neutral radicals [34,35], with ionized donors acting as oxidizing agents. At this interface, the neutralization of positive donors at the NW surface and negative borates in the membrane effectively reduces the electric dipole density in the gate capacitor, consequently decreasing permittivity and hence  $C_g$ .

In other words, an electrochemical interaction at the NW/membrane interface can be modelled as a negative differential (pseudo)-capacitance (NDC) in parallel with  $C_g$ . This is similar to NDC observed at room-temperature in InAs quantum heterostructures and attributed to the charging/discharging of carriers in confined states by measurement perturbation [36]. A similar model has also been used to explain  $I_{DS}$  hysteresis arising from NDC in so-called solid electrolyte FETs [37]. In these devices, sweeping the gate potential causes the drift and diffusion of mobile oxygen ions and corresponding vacancies in an oxide membrane used as the gate dielectric on oxide semiconductor channels. The frequency dependence of this ion migration polarizes the semiconductor/membrane interface and gives rise to NDC. In contrast,  $\text{Na}^+$ -ionophore complexes in our ion-membranes limit the mobility of ionic species, leading us to propose an electrochemical mechanism for the NDC observed here.

From Fig. 2a, b, we observe that this decrease of  $C_g$  dominates any reduction in ionized impurity scattering from neutralization of charges as lower transconductance ( $g_m \equiv dI_{DS}/dV_{LG}$ ) is generally seen in downward transfer sweeps. This decreased slope results in  $\Delta V_T$  as  $V_{LG}$  is swept



**Fig. 2.** Transfer curves of an un-polarized InAs NW-ISFET with  $V_{DS} = 10$  mV and (a) increasing or (b) decreasing  $[\text{Na}^+]$  in solution. Arrows indicate the direction and solid (dashed) lines represent the leading (trailing) half of the sweep. Corresponding calibration curves extracted from (c) threshold voltage of the leading sweep, (d) threshold voltage shift between sweeps, and (e) hysteresis quasi-capacitance. Dashed lines are linear fits and serve as a guide to the eye. Error bars larger than data markers represent measurement uncertainty in activity (horizontal) or standard error in extracted parameters (vertical). Ideal Nernst slopes for  $\text{Na}^+$  at ambient are annotated in (c) and (d).

back from its turning point. We associate this potential change with an induced hysteresis charge ( $\Delta Q_f$ ) within the gate stack and its amount depends on the competition between borate oxidation and simple electron capture into donor-like traps caused by sweeping  $V_{LG}$ . Therefore,  $\Delta V_T$  drops over both  $C_{DL}$  and  $C_g$ , and while tracking changes to  $C_g$  we can use a description of the flat-band voltage of an ISFET [33] to show:

$$\Delta V_T \equiv V_{T,\text{up}} - V_{T,\text{down}} = -\Delta \left( \frac{Q_f}{C_g} \right) = \frac{\alpha \Delta Q_f + (\alpha - 1) Q_{f,\text{up}}}{C_{g,\text{up}}} \quad (2)$$

where  $\Delta Q_f = Q_{f,\text{down}} - Q_{f,\text{up}}$  and  $\alpha = \frac{C_{g,\text{up}}}{C_{g,\text{down}}}$

wherein other contributions to the flat-band voltage are assumed constant—typical when approximating  $\psi_{\text{int}}$  by  $V_T$ —except the net density of “fixed” charges ( $Q_f = e(N_+ - N_-)$ , where  $N$  is the number density of positive or negative charge). The history dependence of  $C_g$  between sweeps is simplified as  $\alpha$ , which is reasonable and discussed further in SI §S2.1. A negative sign arises algebraically and tracks the shift direction. Although the contribution of  $\psi_{\text{int}}$  is directly eliminated by differencing of  $V_T$ , its effect is preserved in the range of  $V_{LG}$  (i.e.  $V_{LG,\text{eff}} = V_{LG} + \psi_{\text{int}}$ ) and manifests indirectly in the oxidation overpotential and the driving force for capture and emission into trap states. Given fast rates of complexation, varying  $\psi_{\text{int}}$  via  $[\text{Na}^+]$  of test solutions can thus be considered as probing these two processes.

The latter process determines the filling of ionized donors by trapping, which is thus proportional to the interface charge due to  $\text{Na}^+$  ions ( $Q_{\text{int}}$ ). Furthermore, the total amount of neutralized charge is the sum of filled donors and  $\Delta Q_f$ , and is itself proportional to the initial density of ionized donors ( $Q_{f,\text{up}}$ ) available to be neutralized. Therefore, when oxidation and trapping occur on similar timescales, the induced hysteresis charge can be seen as a reflection of the interface charge mirrored in trap states (i.e.  $\Delta Q_f \propto \gamma Q_{f,\text{up}} - Q_{\text{int}}$ ). This relationship is evidenced in Fig. 2d, for monotonically decreasing, positive  $\Delta V_T$  with increasing  $a_{\text{Na}^+}$ .

This view of  $\Delta Q_f$  inspires another quantification of  $I_{DS}$  hysteresis as charge injected into the gate dielectric. To calculate total charge 1 (i.e. disregarding sign), we take the unsigned area enclosed between transfer sweeps:

$$A_H \equiv \int_{V_{\text{min}}}^{V_{\text{max}}} |I_{DS,\text{down}} - I_{DS,\text{up}}| dV_{LG} \quad (3)$$

It is obvious that this integral does not directly correspond to injected charge, because  $I_{DS}$  is modulated by  $V_{LG}$  via a transfer characteristic. Thus, a model for  $I_{DS}$  of a NWFET in the linear regime [38] is required to evaluate the integral:

$$I_{DS} = \frac{\mu_{FE} C_g}{L^2} \left( V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} = g_m \left( V_{GS} - V_T - \frac{V_{DS}}{2} \right) \quad (4)$$

where  $V_{GS} = V_{LG}$  and device properties such as field-effect mobility ( $\mu_{FE}$ ), channel length ( $L$ ), and  $C_g$  (including the radial dependence of these quantities) can be aggregated in  $g_m$ . Therefore:

$$A_H = (V_{\text{max}} - V_{\text{min}}) [g_{m,\text{up}}(V_{T,\text{up}} - V_\beta) - g_{m,\text{down}}(V_{T,\text{down}} - V_\beta)] \quad (5)$$

where  $V_\beta = (V_{\text{max}} + V_{\text{min}} - V_{DS})/2$

Previous studies of these InAs NWs [38] showed that, even at room temperature,  $\mu_{FE}$  is inversely proportional to surface charge density as ionized impurity scattering dominates (i.e.  $\mu_{FE} \propto 1/Q_f$ ). Therefore,  $g_m \propto C_g/Q_f$ , and (5) gives:

$$A_H \propto (V_{\text{max}} - V_{\text{min}})(V'_T - V_\beta) \cdot \Delta \left( \frac{C_g}{Q_f} \right)$$

$$\Delta \left( \frac{C_g}{Q_f} \right) = \frac{C_{g,\text{up}}}{Q_{f,\text{up}}} \left[ 1 + \frac{Q_{f,\text{up}}}{\alpha \Delta Q_f + (\alpha - 1) Q_{f,\text{up}}} \right]^{-1} = \frac{C_{g,\text{up}}}{Q_{f,\text{up}}} \left[ 1 + \frac{Q_{f,\text{up}}}{\Delta V_T \cdot C_{g,\text{up}}} \right]^{-1} \quad (6)$$

where, as in (2),  $V'_T$  represents the assumed constant contributions to the flat-band voltage and  $\Delta Q_f$  and  $\alpha$  are defined. When  $|\Delta V_T \cdot C_{g,\text{up}}| \ll |Q_{f,\text{up}}|$ , (6) can be simplified:

$$A_H \propto (V_{\text{max}} - V_{\text{min}})(V'_T - V_\beta) \left( \frac{C_{g,\text{up}}}{Q_{f,\text{up}}} \right)^2 \Delta V_T \quad (7)$$

This inequality is confirmed empirically in Fig. 3 by observed linearity between  $A_H$  and  $\Delta V_T$  throughout all studied polarization regimes for a representative and alternative device. As elaborated in SI §S2.2, this relation holds because of large surface state densities in InAs. It is now apparent that, like  $\Delta V_T$ ,  $A_H$  is dependent on  $Q_{\text{int}}$  through  $\Delta Q_f$ .

As a non-equilibrium quantity,  $\Delta Q_f$  is dependent on the dynamic parameters of the measurement: the range of  $V_{LG}$ —practically limited by minimizing electrochemical interference—and on  $dV_{LG}/dt$ —initially chosen to probe the response of faster trap states [24] more relevant for sensing.  $dV_{LG}/dt$  also dictates the balance between the rates of borate oxidation versus simple electron capture into traps. Thus, normalizing  $A_H$  by these parameters (i.e.  $\tilde{C}_H \equiv A_H \left( \frac{dV_{LG}}{dt} (\max V_{LG} - \min V_{LG}) \right)^{-1}$ ) amounts to a change of variable in (3) and elimination of the first term in (5), leaving units of capacitance. We term the resulting quantity ( $\tilde{C}_H$ ) as hysteresis quasi-capacitance, which describes how the observed change in carrier density, modulated by  $\mu_{FE}$ , in the NWFET channel by the sweeping action of  $V_{LG}$  is related to  $\Delta Q_f$ . We represent the data in this form as it is useful to think of  $I_{DS}$  hysteresis in terms of stored charge.

Furthermore, the extensivity of  $\tilde{C}_H$  (cf.  $I_{DS}$ ) must be contained in the remaining pre-factors of (7), inasmuch as  $\Delta V_T$  is intensive because terms in (2) scale by the same factors (e.g. number of NWs, active surface area, etc.). Hence, using regression slopes from Fig. 3 as proportionality constants to restate  $\tilde{C}_H$  sensitivity in potential terms aids the comparison of experimental results and the Nernstian ideal (i.e. left-hand side of (8)). Accordingly, the magnitude of  $\tilde{C}_H$  and its relationship to  $\Delta V_T$  is associated with the set of dynamic parameters used to obtain the data. In the present study, we maintained these settings as a constant to allow for calibration of  $\tilde{C}_H$  sensitivity throughout polarization regimes. Fig. 2c–e show  $\text{Na}^+$  calibration data for un-polarized NW-ISFETs extracted from  $V_T$  of the leading sweep,  $\Delta V_T$ , and  $\tilde{C}_H$ , respectively. Fit parameters for all presented data are given in Table 1.

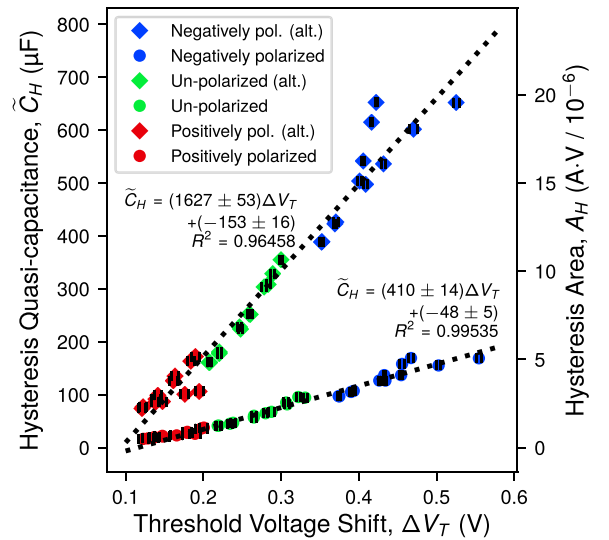


Fig. 3. Hysteresis quasi-capacitance (area) vs. threshold voltage shift for two InAs NW-ISFETs under various polarization conditions. Horizontal error bars represent standard error in extracted  $\Delta V_T$ . Dashed lines show a least squares fit with annotated fit parameters.

### 3.2. Un-polarized InAs NW-ISFET calibrations

Un-polarized  $V_T$  sensitivity is close to the Nernstian ideal (ca.  $-54$  mV/dec) and in excellent agreement with our previous work on this FPS membrane [29], in addition to reports of bis(12-crown-4) in other systems [39,40]. However, a vertical shift between regression lines for increasing and decreasing  $[\text{Na}^+]$  in Fig. 2c is apparent, indicating poor stability of the  $V_T$  response and concomitant loss of calibration accuracy. These potential shifts were observed, regardless of membrane pre-conditioning, in both InAs NW and planar Si ISFETs (see Fig. S5, Table S2) suggesting the source of the error as a slow net electrophoresis of  $\text{Na}^+$  into/from the membrane by applied  $V_{LG}$ . Assuming that  $a_{\text{Na}^+, \text{mem}}$

$$\begin{aligned} \frac{\partial A_H}{\partial a_{\text{Na}^+}} \left( \frac{\partial A_H}{\partial \Delta V_T} \right)^{-1} &= \frac{\partial \Delta V_T}{\partial a_{\text{Na}^+}} + \left\{ \left[ \frac{\Delta V_T}{V_T - V_{\beta}} \right] \frac{\partial V_T'}{\partial a_{\text{Na}^+}} - 2 \left[ \frac{\Delta V_T \cdot C_{g,\text{up}}}{Q_{f,\text{up}}} \right] \frac{\partial (Q_{f,\text{up}}/C_{g,\text{up}})}{\partial a_{\text{Na}^+}} \right\} \\ &= \frac{\partial \Delta V_T}{\partial a_{\text{Na}^+}} - \left\{ \left[ \frac{\Delta V_T}{V_T - V_{\beta}} \right] \frac{\partial \psi_{\text{int}}}{\partial a_{\text{Na}^+}} + 2 \left[ \alpha \frac{Q_{f,\text{down}}}{Q_{f,\text{up}}} - 1 \right] \frac{\partial (Q_{f,\text{up}}/C_{g,\text{up}})}{\partial a_{\text{Na}^+}} \right\} \end{aligned} \quad (8)$$

is no longer constant in (1), a relative change can be calculated using the similar regression slopes and change in intercept (ca. 16 mV). The result reveals a near doubling of  $a_{\text{Na}^+, \text{mem}}$  as the sensing experiment proceeds, with the same ratio representing the accuracy loss.

In contrast, calibrations of  $\Delta V_T$  and  $\tilde{C}_H$  (Fig. 2d, e) are stable with no significant shift. This arises from differencing in (2) and (3), as errors from symmetric (i.e. slow) potential drifts apply equally to both halves of a sweep and cancel out. Stable responses in  $V_T$ , referenced to the RE potential, cannot accommodate these drifts that are likely when  $[\text{Na}^+]$  changes through orders of magnitude. This illustrates the reduced first-order errors in hysteretic responses, as each datum is derived from changes to the NWFET surface in its immediate context. In this way, the hysteresis quasi-capacitance is akin to a high-pass filter and attenuates the signal from slow electrophoretic drifts.

However,  $\Delta V_T$  sensitivity (ca.  $-48$  mV/dec) is decreased by about 10% compared to  $V_T$ . As near-Nernstian sensitivities were observed in  $V_T$ , this suggests that mirroring of  $Q_{\text{int}}$  into trap states is likely incomplete at measurement timescales and dynamic parameters may yet be optimized. Indeed,  $V_{T,\text{down}}$  exhibits small  $a_{\text{Na}^+}$  dependency (ca.  $-6$  mV/dec), indicating that  $\Delta V_T$  has some additional unaccounted dependence. This is a higher-order error related to trap dynamics. In comparison, converted potentiometric sensitivities for the  $\tilde{C}_H$  response ( $-57.8 \pm 3.5$  and  $-56.6 \pm 5.6$  mV/dec for increasing and decreasing  $[\text{Na}^+]$ ,

**Table 1**

Fit parameters of presented calibration data.

Curve	$[\text{Na}^+]$ direction	Slope	Intercept	$R^2$
<i>Un-polarized NW-ISFET (Fig. 2)</i>				
$V_T$	Increasing	$-54.3 \pm 2.3$ mV/dec	$184 \pm 3$ mV	0.99647
	Decreasing	$-53.0 \pm 1.4$ mV/dec	$200 \pm 2$ mV	0.99783
$\Delta V_T$	Increasing	$-48.8 \pm 2.7$ mV/dec	$214 \pm 4$ mV	0.99078
	Decreasing	$-47.4 \pm 0.7$ mV/dec	$213 \pm 1$ mV	0.99928
$\tilde{C}_H$	Increasing	$-23.7 \pm 1.2$ $\mu\text{F}/\text{dec}$	$36.1 \pm 1.6$ $\mu\text{F}$	0.99426
	Decreasing	$-23.2 \pm 2.2$ $\mu\text{F}/\text{dec}$	$34.6 \pm 2.7$ $\mu\text{F}$	0.98586
<i>Negatively polarized NW-ISFET (Fig. 4)</i>				
$V_T$	Increasing	$-92.0 \pm 5.7$ mV/dec	$170 \pm 5$ mV	0.99855
	Decreasing	$-68.5 \pm 5.7$ mV/dec	$184 \pm 6$ mV	0.96864
$\Delta V_T$	Increasing	$-69.7 \pm 4.9$ mV/dec	$362 \pm 5$ mV	0.99465
	Decreasing	$-45.2 \pm 3.2$ mV/dec	$371 \pm 3$ mV	0.98304
$\tilde{C}_H$	Increasing	$-31.8 \pm 0.8$ $\mu\text{F}/\text{dec}$	$92.3 \pm 0.9$ $\mu\text{F}$	0.99930
	Decreasing	$-33.1 \pm 0.6$ $\mu\text{F}/\text{dec}$	$90.9 \pm 0.7$ $\mu\text{F}$	0.99939

NB: Additional calibrations for other devices and polarizations presented in Table S2.

respectively) return to Nernstian values. Moreover, as Fig. S7 shows, the  $\tilde{C}_H$  response is remarkably stable, maintaining sensitivity after storage periods of two weeks to two months in ambient conditions.

It is likely that an unnamed pre-factor in (7) holds an inverse dependence related to the higher-order error in  $\Delta V_T$ . In fact, theoretical  $A_H$  by (5) is an overestimate of observed  $A_H$  (Fig. S4a) as non-ideality is neglected (e.g. mobility degradation by surface or self scattering at increased carrier densities). Contrasting Fig. 3 with theoretical  $A_H$  vs.  $\Delta V_T$  (Fig. S4b) illustrates that the observed linearity across polarization regimes is attributable to non-ideality. This is elucidated by partial differentiation of (7):

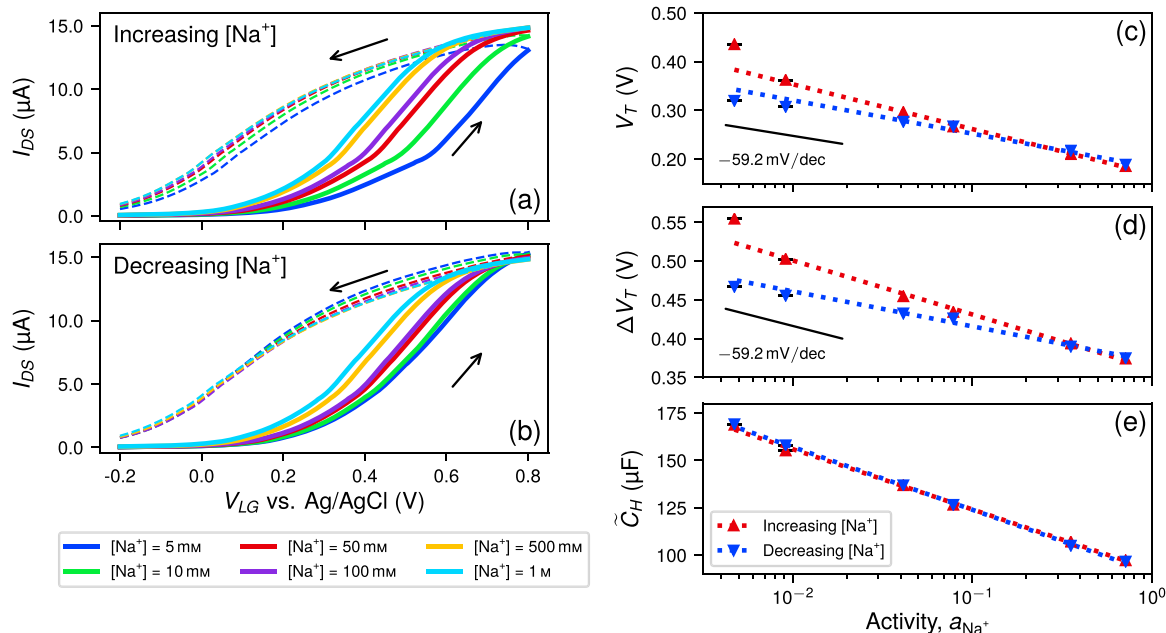
where  $\partial A_H / \partial \Delta V_T$  contains unnamed proportionality factors and (2) has been substituted in the second expression. Terms in curly braces are named factors that modulate  $A_H$  sensitivity. Assuming that solvated ions are unable to dope InAs, the activity dependence of  $V_T'$  is simply the Nernst sensitivity from (1). However, with  $|\Delta V_T \cdot C_{g,\text{up}}| \ll |Q_{f,\text{up}}|$  and  $V_T = V_T - \frac{Q}{C_g}$ , both terms in square braces will approach zero. Note, typically  $V_T \sim V_{\beta}$ , as the measurement range (represented by  $V_{\beta}$ ) is chosen to best capture the transfer curve. Therefore, the influence of these terms is similarly small (ca. 0.1%, see SI §S2.2) and it is likely that an unnamed factor accounts for  $\tilde{C}_H$  sensitivity that approaches ideal values in the un-polarized case.

### 3.3. Polarized InAs NW-ISFET calibrations

Nonetheless, (8) reveals a basis for modulation of the  $A_H$  ( $\tilde{C}_H$ ) response: while the first term in curly braces is coupled to the Nernst sensitivity and thus constant, the second is coupled to  $Q_{f,\text{up}}$  and, critically, its dependence on  $a_{\text{Na}^+}$ , which may be externally manipulated. This is simply achieved by electrostatic polarization via  $V_{LG}$  or  $V_{BG}$ . Here,  $V_{LG}$  is used as timing is more readily coordinated by holding a pre-sweep bias as compared to switching potential sources. However,  $V_{BG}$  may allow greater ranges as it is insulated from the electrolyte. In either case, the membrane composition will change simultaneously due to electrophoresis dependent on the applied potential, hold time, and bulk  $[\text{Na}^+]$ . In this actively operated regime, the capacity to filter out first-order errors enables extraction of useful information.

Data showing sensitivity enhancement is given in Fig. 4. With negative polarization of  $V_{LG} = -200$  mV, the channel level is raised, increasing the rate of donor ionization and  $Q_{f,\text{up}}$ . This also enhances the magnitude of  $\partial(Q_{f,\text{up}}/C_{g,\text{up}})/\partial a_{\text{Na}^+}$ , as level raising by  $V_{LG,\text{eff}}$  is less for larger  $[\text{Na}^+]$ . Simultaneously, the ion-membrane is pushed out of equilibrium into a  $\text{Na}^+$  depleted state. The resulting gradient drives additional diffusive flux of  $\text{Na}^+$  into the membrane during measurements, producing the observed super-Nernstian responses [41] in  $V_T$  (Fig. 4c).

Moreover, differences in transfer curve lineshape between Fig. 4a, b and significant hysteresis in  $V_T$  sensitivity clearly demonstrate that contributions from non-equilibrium ion fluxes are strongly dependent on initial conditions. After filtering out slow potential drifts by  $\Delta V_T$  (Fig. 4d), sensitivity similar to the un-polarized state (ca.  $-45$  mV/dec) is obtained in the decreasing  $[\text{Na}^+]$  run. However, the increasing run remains super-Nernstian, corresponding to asymmetric (i.e. fast)



**Fig. 4.** Transfer curves of a negatively polarized InAs NW-ISFET with  $V_{DS} = 10$  mV and (a) increasing or (b) decreasing  $[Na^+]$  in solution. Arrows indicate the direction and solid (dashed) lines represent the leading (trailing) half of the sweep. Corresponding calibration curves extracted from (c) threshold voltage of the leading sweep, (d) threshold voltage shift between sweeps, and (e) hysteresis quasi-capacitance. Dashed lines are linear fits and serve as a guide to the eye. Error bars larger than data markers represent measurement uncertainty in activity (horizontal) or standard error in extracted parameters (vertical). Ideal Nernst slopes for  $Na^+$  at ambient are annotated in (c) and (d).

potential shifts from a net injection of  $Na^+$  into the membrane by sweeping  $V_{LG}$ . This is further evidenced by shifting of  $V_{T,down}$  in these runs. From about 50 mM  $Na^+$  onwards, a quasi-equilibrium is reached and these shifts disappear.

Accordingly,  $\Delta Q_f$  in these runs is lower than expected for the observed value of  $\Delta V_T$  as part of applied  $V_{LG}$  rather works to inject charge as  $Na^+$ . Hence,  $\partial(Q_{f,up}/C_{g,up})/\partial a_{Na^+}$  is smaller in these initial data. That is, sections of the  $\Delta V_T$  response that experience additional potential shifts from non-equilibrium ion fluxes realize less sensitivity enhancement in terms of  $\tilde{C}_H$  (Fig. 4e) and the resulting non-linear behaviour equalizes the calibration slopes ( $-77.5 \pm 3.2$  and  $-80.7 \pm 3.0$  mV/dec for increasing and decreasing  $[Na^+]$ , respectively), which is enhanced by about 40% over the un-polarized state.

The expected degree of  $\tilde{C}_H$  sensitivity enhancement from coupling to  $\partial(Q_{f,up}/C_{g,up})/\partial a_{Na^+}$  can be estimated using the spectral density of surface states near the conduction band edge in these InAs NWs (cf.  $10^{12} \text{ cm}^{-2} \text{ eV}^{-1}$ ) [38], assuming strong coupling of  $V_{LG,eff}$  to the energy level of the channel—reasonable given the range of  $V_{LG}$  and observed transfer characteristics. In conjunction with estimated  $C_g$  (see SI §S2.1), this value is suitably large to overcome the minimizing term in (8), giving enhancement on the order of 10 mV/dec in agreement with the observed  $\tilde{C}_H$  response.

The fact that neither stability nor true sensitivity enhancement is observed in the  $\Delta V_T$  response emphasizes the significance of coupling to the initial density of ionized traps to produce modulation of  $\tilde{C}_H$  sensitivity. For instance, the reverse effect of suppression occurs if the signs of the modulating factors in (8) are mismatched. This was observed when acceptor-like traps were activated by positive polarization of InAs NW-ISFETs (see SI §S3.2). Ultimately,  $\Delta Q_f$  is a mirror of  $Q_{int}$  and subject to the same thermodynamic limits. However, directly coupling the sensor response to trap states allows for sensitivity modulation by the active operation of NW-ISFETs. Our success in demonstrating the proof-of-concept points towards the need for a deeper understanding of the trap state distribution—and ways to engineer it—in nanostructured sensors to further optimize this modulation effect.

#### 4. Conclusions

Using InAs NWs coupled to polymeric ion-selective membranes as ISFETs to sense  $Na^+$ , we showed that potentiometric sensitivities derived from quantified current hysteresis ( $\Delta V_T$  and  $\tilde{C}_H$ ) are more stable than the commonly used  $V_T$ , which tracks the potential due to ions at the membrane/electrolyte interface. We show how these data may be readily gleaned from FET transfer characteristics, provided that consistent dynamic parameters are maintained and the gate potential is applied in a closed loop. We developed a model that elucidated the origin of ion sensitivity in current hysteresis as the mirroring of interfacial charges into surface trap states. Greater stability—in terms of repeatability against potential drifts caused by variation in membrane composition—was achieved because the mirrored charges were counted by the change of ionized trap density, effectively acting as a filter to reduce first-order errors.

The model further revealed that the  $\tilde{C}_H$  response is coupled to the initial density of ionized traps in a manner that allows external manipulation, giving a basis for the active operation of NW-ISFETs to modulate sensitivity. This concept was proved by simple electrostatic polarization via applied  $V_{LG}$ , whereby energy bands in the InAs NW channel are repositioned for a time to enhance variation in the initial density of ionized traps with the interfacial potential. Meanwhile, the direction of modulation is largely controlled by the role of ionized traps in determining the capacitance of the NW/membrane interface. Both enhancement and suppression effects were observed, in accordance with the type of traps at play—donors and acceptors, respectively. In either case, active operation drives both electronic and ionic charges into non-equilibrium, producing significant errors in the  $V_T$  response. However, the stability of hysteretic responses means extraction of meaningful sensing information remains possible.

Here, we explored the implications of the model experimentally in InAs NW-ISFETs thanks to the existence of both donor and acceptor-like trap states and favourable alignment of energy bands with the operating range and timescale of  $V_{LG}$ . However, we emphasize that this result is general to FET sensors with trap states in communication with the

semiconductor channel and that significantly modulate electronic transport by ionized scattering, as is commonly the case with nanostructured devices. In the field of FET-based sensing, much effort is spent on isolating the effect of  $\psi_{\text{int}}$ , sometimes at the expense of so-called confounding factors like traps, whereas our results illustrate that FET hysteresis can be taken as an information source and gives a physical basis for overcoming the Nernstian limit in potentiometric sensors.

### Author contributions

Alex C. Tseng: Investigation, methodology, writing – original draft. Kensuke Ito: Investigation, methodology. David Lynall: Methodology, writing – review & editing. Igor G. Savelyev: Resources. Marina Blumin: Resources. Shiliang Wang: Conceptualization, writing – review & editing. Harry E. Ruda: Conceptualization, supervision, writing – review & editing. Toshiya Sakata: Conceptualization, supervision, writing – review & editing.

### Conflict of interest

The authors declare that there is no conflict of interest.

### Declaration of Competing Interest

The authors report no declarations of interest.

### Acknowledgements

Portions of this work were supported by the Natural Sciences and Engineering Research Council of Canada (NSERC), Defence Research and Development Canada (DRDC), and the Mirai Program of Japan Science and Technology (JST). Particularly, A.C.T. acknowledges the Michael Smith Foreign Study Supplement from NSERC for funding an exchange to Sakata Laboratory.

### Appendix A. Supplementary data

Supplementary data associated with this article can be found, in the online version, at <https://doi.org/10.1016/j.snb.2021.129704>.

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